

IRF9150 IRF9151

Avalanche Energy Rated P-Channel Power MOSFETs

Features

- -25A, -60V and -100V
- $r_{DS(ON)} = 0.150\Omega$
- Single Pulse Avalanche Energy Rated
- SOA is Power-Dissipation Limited
- Nanosecond Switching Speeds
- Linear Transfer Characteristics
- High Input Impedance

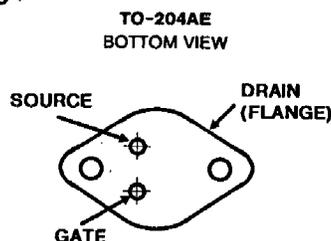
Description

The IRF9150 and IRF9151 are advanced power MOSFETs designed, tested, and guaranteed to withstand a specified level of energy in the breakdown avalanche mode of operation. These are p-channel enhancement-mode silicon-gate power field-effect transistors designed for applications such as switching regulators, switching converters, motor drivers, relay drivers, and drivers for high-power bipolar switching transistors requiring high speed and low gate-drive power. These types can be operated directly from integrated circuits.

The P-channel IRF9150 is an approximate electrical complement to the N-channel IRF9150.

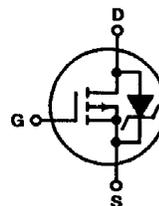
The IRF types are supplied in the JEDEC TO-204AE metal package.

Package



Terminal Diagram

P-CHANNEL ENHANCEMENT MODE



Absolute Maximum Ratings ($T_C = 25^\circ\text{C}$) Unless Otherwise Specified

	IRF9150	IRF9151	UNITS
Drain-Source Voltage V_{DS}	-100	-60	V
Continuous Drain Current			
$T_C = 25^\circ\text{C}$ I_D	-25	-25	A
$T_C = 100^\circ\text{C}$ I_D	-18	-18	A
Pulsed Drain Current I_{DM}	-100	-100	A
Gate-Source Voltage V_{GS}	± 20	± 20	V
Maximum Power Dissipation P_D	150	150	W
(See Figure 18)			
Linear Derating Factor	1.2	1.2	W/°C
Single Pulse Avalanche Energy Rating (3) E_{AS}	1300	1300	mJ
(See Figure 14)			
Avalanche Current (Repetitive or Nonrepetitive) I_{AR}	-25	-25	A
Operating and Storage Junction Temperature Range T_J, T_{STG}	-55 to +150	-55 to +150	°C
Maximum Lead Temperature for Soldering T_L	300	300	°C
(0.063" (1.6mm) from case for 10s)			

NOTES:

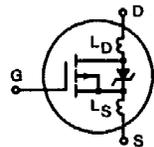
1. Pulse Test: Pulse width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$
2. Repetitive Rating: Pulse width limited by max. junction temperature. See Transient Thermal Impedance Curve (Figure 5)
3. $V_{DD} = 25\text{V}$, Start $T_J = +25^\circ\text{C}$, $L = 3.2\text{mH}$, $R_G = 25\Omega$, Peak $I_L = 19\text{A}$ (See Figures 14 and 15)



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Specifications IRF9150, IRF9151

Electrical Characteristics $T_C = +25^\circ\text{C}$, Unless Otherwise Specified

CHARACTERISTIC	SYMBOL	TEST CONDITIONS	LIMITS			UNITS
			MIN	TYP	MAX	
Drain-Source Breakdown Voltage IRF9150 IRF9151	BV_{DSS}	$V_{GS} = 0V, I_D = -250\mu A$	-100	-	-	V
			-60	-	-	V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS} = V_{GS}, I_D = -250\mu A$	-2.0	-	-4.0	V
Gate-Source Leakage Forward	I_{GSS}	$V_{GS} = -20V$	-	-	-100	nA
Gate-Source Leakage Reverse	I_{GSS}	$V_{GS} = 20V$	-	-	100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = \text{Max Rating}, V_{GS} = 0V$ $V_{DS} = \text{Max Rating} \times 0.8, V_{GS} = 0V,$ $T_C = +125^\circ\text{C}$	-	-	-250	μA
			-	-	-1000	μA
On-State Drain Current (Note 1)	$I_D(ON)$	$V_{DS} > I_D(ON) \times r_{DS(ON)} \text{ Max}, V_{GS} = 10V$	-25	-	-	A
Static Drain-Source On-State Resistance (Note 1)	$r_{DS(ON)}$	$V_{GS} = -10V, I_D = -10A$	-	0.09	0.15	Ω
Forward Transconductance (Note 1)	g_{fs}	$V_{DS} = -10V, I_D = -12.5A$	4	10	-	S
Input Capacitance	C_{ISS}	$V_{GS} = 0V, V_{DS} = -25V, f = 1.0\text{MHz}$ See Figure 10	-	2400	-	pF
Output Capacitance	C_{OSS}		-	850	-	pF
Reverse Transfer Capacitance	C_{RSS}		-	400	-	pF
Turn-On Delay Time	$t_d(ON)$	$V_{DD} = -50V, I_D = -25A, R_G = 6.8\Omega,$ $R_D = 2\Omega$. See Figures 16 and 17. (MOSFET switching times are essentially independent of operating temperature.)	-	16	24	ns
Rise Time	t_r		-	110	160	ns
Turn-Off Delay Time	$t_d(OFF)$		-	65	100	ns
Fall Time	t_f		-	46	70	ns
Total Gate Charge (Gate-Source + Gate-Drain)	Q_g		$V_{GS} = -10V, I_D = -25A, V_{DS} = 0.8 \text{ Max Rating}$. See Figures 11 & 19 for test circuit. (Gate charge is essentially independent of operating temperature.)	-	82	120
Gate-Source Charge	Q_{gs}		-	14	-	nC
Gate-Drain ("Miller") Charge	Q_{gd}		-	42	-	nC
Internal Drain Inductance	L_D	Measured between contact screw on header that is closer to source & gate pins & center of die.	-	5.0	-	nH
Internal Source Inductance	L_S	Measured from the source pin, 6mm (0.25") from header & source bonding pad.	-	13	-	nH
						
Junction-to-Case	$R_{\theta JC}$		-	-	0.83	$^\circ\text{C/W}$
Case-to-Sink	$R_{\theta CS}$	Mounting surface flat, smooth and greased	-	0.1	-	$^\circ\text{C/W}$
Junction-to-Ambient	$R_{\theta JA}$	Free Air Operation	-	-	30	$^\circ\text{C/W}$

Source Drain Diode Ratings and Characteristics

Continuous Source Current (Body Diode)	I_S	Modified MOSFET symbol showing the integral reverse P-N junction rectifier.	-	-	-25	A
Pulse Source Current (Body Diode) (Note 3)	I_{SM}		-	-	-100	A
Diode Forward Voltage (Note 2)	V_{SD}	$T_C = +25^\circ\text{C}, I_S = 25A, V_{GS} = 0V$	-	0.9	1.5	V
Reverse Recovery Time	t_{rr}	$T_J = +25^\circ\text{C}, I_F = 25A, di_F/dt = 100A/\mu s$	-	150	300	ns
Reverse Recovered Charge	Q_{RR}	$T_J = +25^\circ\text{C}, I_F = 25A, di_F/dt = 100A/\mu s$	0.3	0.7	1.5	μC
Forward Turn-on Time	t_{ON}	Intrinsic turn-on time is negligible. Turn-on speed is substantially controlled by $L_S + L_D$.	-	-	-	-

NOTES: 1. Pulse Test: Pulse width $\leq 300\mu s$, Duty Cycle $\leq 2\%$

2. Repetitive Rating: Pulse width limited by max. junction temperature. See Transient Thermal Impedance Curve (Figure 5)

3. $V_{DD} = 25V$, Start $T_J = +25^\circ\text{C}$, $L = 3.2\text{mH}$, $R_G = 25\Omega$, Peak $I_L = 25A$ (See Figures 14 and 15)